

This is a preview of "ISO 22493:2014". [Click here to purchase the full version from the ANSI store.](#)

Second edition
2014-04-15

Microbeam analysis — Scanning electron microscopy — Vocabulary

*Analyse par microfaisceaux — Microscopie électronique à balayage
— Vocabulaire*



Reference number
ISO 22493:2014(E)

© ISO 2014

This is a preview of "ISO 22493:2014". [Click here to purchase the full version from the ANSI store.](#)



COPYRIGHT PROTECTED DOCUMENT

© ISO 2014

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized otherwise in any form or by any means, electronic or mechanical, including photocopying, or posting on the internet or an intranet, without prior written permission. Permission can be requested from either ISO at the address below or ISO's member body in the country of the requester.

ISO copyright office
Case postale 56 • CH-1211 Geneva 20
Tel. + 41 22 749 01 11
Fax + 41 22 749 09 47
E-mail copyright@iso.org
Web www.iso.org

Published in Switzerland

This is a preview of "ISO 22493:2014". [Click here to purchase the full version from the ANSI store.](#)

Contents

	Page
Foreword	iv
Introduction	v
1 Scope	1
2 Abbreviated terms	1
3 Terms and definitions used in the physical basis of SEM	1
4 Terms and definitions used in SEM instrumentation	5
5 Terms and definitions used in SEM image formation and processing	12
6 Terms and definitions used in SEM image interpretation and analysis	16
7 Terms and definitions used in the measurement and calibration of SEM image magnification and resolution	18
Bibliography	20

Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see www.iso.org/patents).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation on the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the WTO principles in the Technical Barriers to Trade (TBT) see the following URL: [Foreword - Supplementary information](#)

The committee responsible for this document is ISO/TC 202, *Microbeam analysis*, Subcommittee SC 1, *Terminology*.

This second edition cancels and replaces the first edition (ISO 22493:2008), of which it constitutes a minor revision.

This is a preview of "ISO 22493:2014". [Click here to purchase the full version from the ANSI store.](#)

Introduction

The scanning electron microscopy (SEM) technique is used to observe and characterize the surface morphology and structure of solid materials, such as metal alloys, ceramics, glasses, minerals, polymers, powders, etc., on a spatial scale of micrometer down to nanometer laterally. In addition, three-dimensional structure can be generated by using a combination of focused ion beam and scanning-electron-based analysis techniques. The SEM technique is based on the physical mechanism of electron optics, electron scattering and secondary electron emission.

As a major sub-field of microbeam analysis (MBA), the SEM technique is widely applied in diverse sectors (high-tech industries, basic industries, metallurgy and geology, biology and medicine, environmental protection, trade, etc.) and has a strong business base that needs standardization.

Standardizing the terminology of a technical field is one of the basic prerequisites for development of standards on other aspects of that field.

This International Standard is relevant to the need for an SEM terminology that contains consistent definitions of terms as they are used in the practice of scanning electron microscopy by the international scientific and engineering communities that employ the technique. This International Standard is the second one developed in a package of standards on electron probe microanalysis (EPMA), scanning electron microscopy (SEM), analytical electron microscopy (AEM), energy-dispersive X-ray spectroscopy (EDS), etc., developed or to be developed by Technical Committee ISO/TC 202, *Microbeam analysis*, Subcommittee SC 1, *Terminology*, to cover the complete field of MBA.